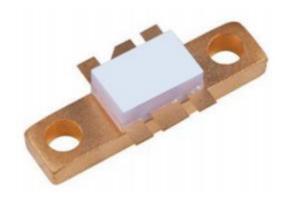


# 15W 500MHz 12V Single-Ended

### D2294UK

#### **Features:**

- Simplified Amplifier Design
- Suitable for Broad Band Applications
- Low C<sub>rss</sub>
- Simple Bias Circuits
- Low Noise
- High Gain 11dB Minimum
- RoHS Compliant



#### **Description:**

Single-Ended RF Silicon Mosfet. 15W at 500MHz, 12.5V

#### Absolute Maximum Ratings (T<sub>A</sub> = 25°C unless otherwise noted)

$P_{D}$	Power Dissipation	50W
BV <sub>DSS</sub>	Drain – Source Breakdown Voltage	40V
BVGSS	Gate – Source Breakdown Voltage	<u>+</u> 20V
I <sub>D</sub> (sat)	Drain Current	12A
T <sub>stg</sub>	Storage Temperature	-65 to +150°C
Тј	Maximum Operating Junction Temperature	200°C

#### **Thermal Properties**

SYMBOL	PARAMETER	MAX	UNITS
$R_{\Theta JC}$	Thermal Resistance, Junction to Case	3.5	°C/W

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### **Electrical Specifications**

#### Electrical Characteristics (T<sub>A</sub> = 25° C unless otherwise noted)

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 10mA	40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 12.5V, V <sub>GS</sub> = 0V			6	mA
I <sub>GSS</sub>	Gate leakage Current	V <sub>GS</sub> = 20V, V <sub>DS</sub> = 0V			1	μΑ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$I_D = 10$ mA, $V_{DS} = V_{GS}$	1		7	V
gfs	Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 1.2A	1.08			S
G <sub>PS</sub>	Common Source Power Gain	P <sub>O</sub> = 15W	11			dB
η	Drain Efficiency	V <sub>DS</sub> = 12.5V, I <sub>DQ</sub> = 0.6A	50			%
VSWR <sup>(1)</sup>	Load Mismatch Tolerance	f = 500MHz	20:1			-
C <sub>iss</sub> <sup>(1)</sup>	Input Capacitance	V <sub>DS</sub> = 12.5V, V <sub>GS</sub> = -5V f = 1MHz			72	pF
C <sub>OSS</sub> <sup>(1)</sup>	Output Capacitance	V <sub>DS</sub> = 12.5V, V <sub>GS</sub> = 0V f = 1MHz			60	pF
C <sub>rss</sub> <sup>(1)</sup>	Reverse Transfer Capacitance	V <sub>DS</sub> = 12.5V, V <sub>GS</sub> = 0V f = 1MHz		6	pF	

#### Notes:

(1) By design only, not a production test

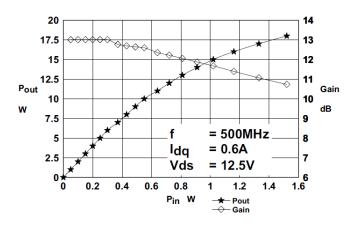
#### **HAZARDOUS MATERIAL WARNING**

The ceramic portion of the device between leads and metal flange is beryllium oxide. Beryllium oxide dust us highly toxic and care must be taken during handling and mounting to avoid damage to this area.

#### THESE DEVICES MUST NEVER BE THROWN AWAY WITH GENERAL INDUSTRIAL OR DOMESTIC WASTE



#### **Performance**



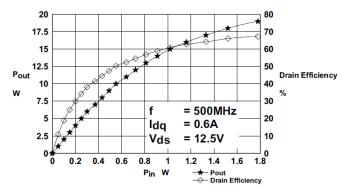


Figure 1
Output power and Gain vs. Input Power

Figure 2
Output power and Efficiency vs. Input Power

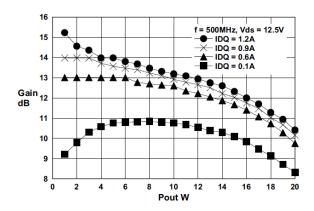


Figure 3
Gain vs Output Power



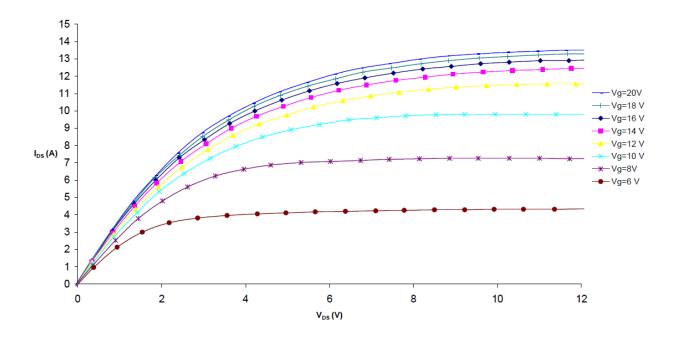


Figure 4 – Typical IV Characteristics

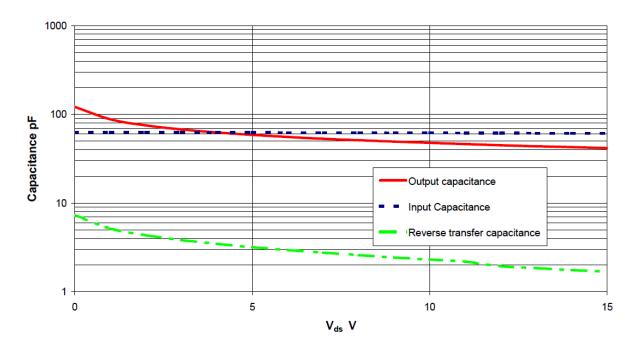
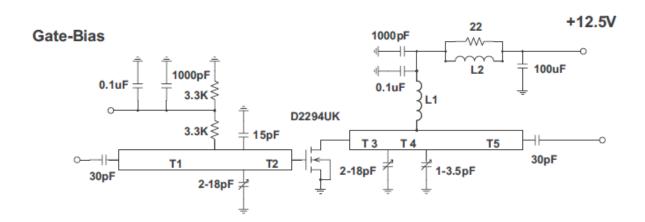


Figure 5 – Typical CV Characteristics



#### **500MHz RF Test Fixture**



Substrate 1.6mm FR4 All microstrip lines W = 2.75mm

T1 47mm T2 9mm T3 9mm

T4 13mm T5 32mm

L1 7 turns 24swg enamelled copper wire, 2mm i.d.

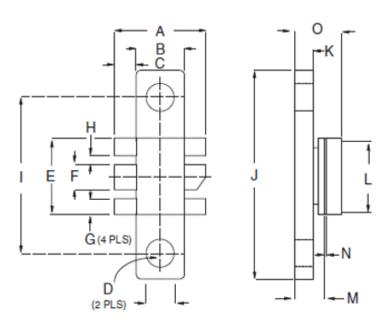
L2 1.5 turns 24swg enamelled copper wire on ferrite core

## D2294UK



## **Packaging**

#### **Mechanical Data**



### SOT171

#### **Top View**

Pad 2 – Source Pin 1 - Source Pin 3 – Gate Pin 4 – Drain Pin 6 – Source Pin 5 – Source

DIM	mm	Tol.	Inches	Tol.
Α	10.92	0.38	0.430	0.015
В	5.84	0.13	0.230	0.005
С	2.54	0.13	0.100	0.005
D	3.30 dia	1.27	0.130 dia	0.050
Е	9.14	0.13	0.360	0.005
F	3.05	0.13	0.120	0.005
G	2.01	0.13	0.079	0.005
Н	1.07	0.13	0.042	0.005
1	18.42	0.13	0.725	0.005
J	24.77	0.13	0.975	0.005
K	2.79	0.13	0.110	0.005
L	9.14	0.13	0.360	0.005
М	4.22	0.25	0.166	0.010
N	0.13	0.05	0.005	0.002
0	7.37	MAX	0.290	MAX





### **Revision Control**

ISSUE	CHANGE DESCRIPTION	APPROVAL	DATE
1	First issue	J.Walker	09-07-2001
2	Addition of I-V and C-V data	P.Smith	02-11-2006
3	Corrected gfs test conditions from 0.6A to 1.2A	P.Smith	22-02-2018
4	Corrected dimension tolerances	P.Smith	25-06-2020